Se	arch	Note	es .	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/789,467	STELZER ET AL.
Examiner	Art Unit
Binh-An D. Nguyen	3713

SEARCHED			
Class	Subclass	Date	Examiner
463	36-47	10/13/2005	. BN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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EAST, see search history	10/13/05	BN
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